

TANISYS[®]

TECHNOLOGY

FLASH MEMORY TEST TECHNOLOGY



FX

FLASH MEMORY TEST SYSTEM



Tanisys continues to lead the way in Flash Memory Test

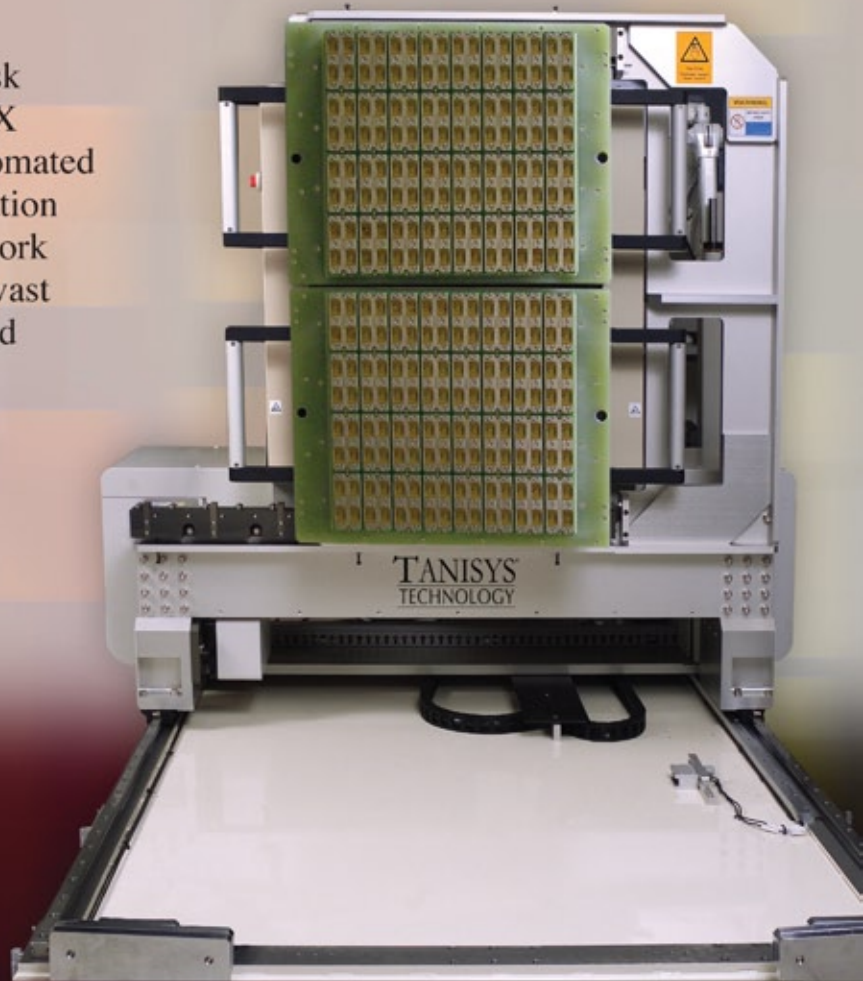
Tanisys Technology, the leader in flash card test equipment, drives high volume Flash manufacturing to a new level. The FX Flash test system, built on the success of the Model M550, is designed for fully automated testing of single and multi-chip package Flash memory devices.

With increasing demand for NAND Flash products coupled with constant price pressure, highly parallel testing is critical. With the FX, Tanisys is setting a new standard for Flash test by providing the capability to test 3000+ devices in parallel.

The FX test system offers world-class test economics while providing the highest test coverage in the industry. Tanisys test systems continue to be the choice of industry leading Flash device and card manufacturers worldwide.

Production Ready

Whether you choose your own handler or ask Tanisys to provide a turnkey solution, the FX test system facilitates easy migration to automated environments. The FX production configuration includes a manipulator that is designed to work with handlers from leading suppliers. With vast experience in developing handler control and production user interface software, Tanisys provides custom solutions to meet your manufacturing needs. Whatever your plan for production, the FX is backed by Tanisys expertise and our extensive global support network.



Configurations To Meet Demand



Whether your needs are for engineering development, qualification, or volume production, the FX test system fits the requirement. As a single blade engineering system, the FX-E can be used to develop your test programs in an office or lab environment. It is also the right solution for product qualification or low volume production. For high volume manufacturing requirements, the FX is available in a multiple blade production chassis. The production test system was designed utilizing a modular approach, which allows the user to add capacity to a single system as product volume increases. The FX test system is currently available in configurations to support 256 NAND Flash devices with the expansion capability to support more than 3000 devices.

Flexibility By Design

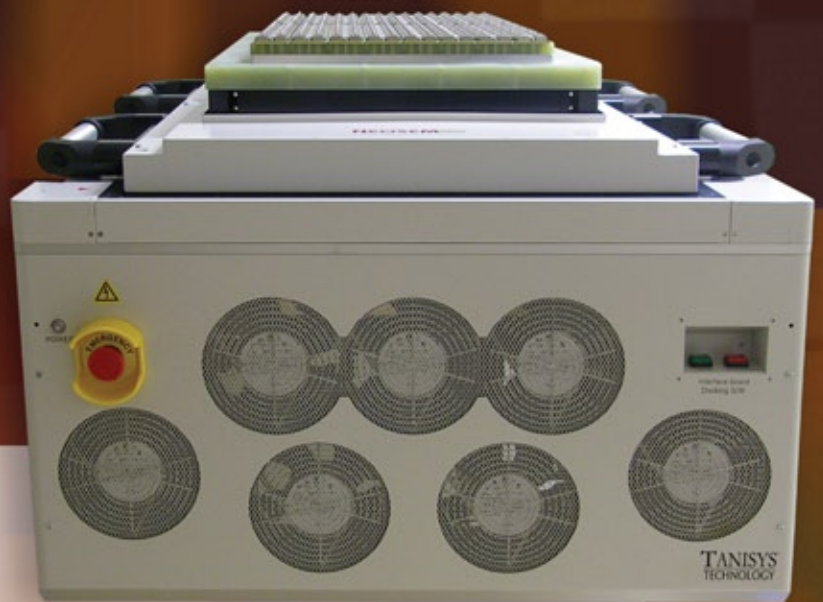
Tanisys Technology designed the FX with flexibility and scalability in mind using the versatile, patented Distributed Network Architecture (DNA™). As the building block of advanced parallel test solutions, DNA enables the user to seamlessly transition from engineering development to high-volume production. In combination with high performance FX hardware, DNA provides virtually unlimited scalability that allows the user to add capacity as needed — a capability not found in other platforms.

Worldwide Support

Tanisys offers technical support to production facilities around the globe through our partnerships in Korea, Japan, Taiwan, China, Singapore and Europe. Services include sales and distribution, full technical support, applications engineering, and spares coverage — the same world-class, hands-on support provided to customers in North America.



The Tanisys FX
"The Future of Test"



FX SPECIFICATIONS

SUPPORTED TECHNOLOGIES:	NAND, NOR, MCP FINAL TEST
PARALLEL CAPABILITY:	<= 3072 DUT's
AVAILABLE CONFIGURATIONS	FX-E SINGLE BLADE FX 2 - 48 BLADES
ARCHITECTURE	PER SITE. TEST SITES ARE DEFINED PER PROTOCOL
PINS	544 PER BLADE
DUT POWER SUPPLIES	64 DPS PER BLADE
PMU	16 PER BLADE
OPERATING SYSTEM	WINDOWS XP
TEST DEVELOPMENT	C ++
MAXIMUM OPERATING FREQUENCY	200MHz
PIN ELECTRONICS	PROGRAMABLE VIH, VIL , VREF
INPUT POWER	100 – 240V AC; 50 TO 60 Hz
OPERATING TEMPERATURE RANGE	20 TO 27 C; AIR COOLED
OPERATING HUMIDITY RANGE	30 TO 70%

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